

## **NDS9400A**

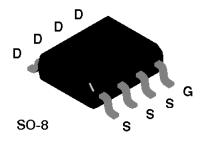
# **Single P-Channel Enhancement Mode Field Effect Transistor**

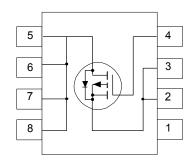
## **General Description**

These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulses in the avalanche and commutation modes. These devices are particularly suited for low voltage applications such as notebook computer power management and other battery powered circuits where fast switching, low in-line power loss, and resistance to transients are needed.

## **Features**

- -3.4A, -30V.  $R_{DS(ON)} = 0.13\Omega$  @  $V_{GS} = -10V$ .
- High density cell design for extremely low R<sub>DS(ON)</sub>.
- High power and current handling capability in a widely used surface mount package.
- Rugged and reliable.





# Absolute Maximum Ratings T<sub>A</sub>= 25°C unless otherwise noted

Symbol	Parameter		NDS9400A	Units
V <sub>DSS</sub>	Drain-Source Voltage		-30	V
V <sub>GSS</sub>	Gate-Source Voltage		± 20	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	± 3.4	А
	- Pulsed		± 10	
P <sub>D</sub>	Maximum Power Dissipation	(Note 1a)	2.5	W
		(Note 1b)	1.2	
		(Note 1c)	1	
T <sub>J</sub> ,T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to 150	°C
THERMA	L CHARACTERISTICS			_
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ami	bient (Note 1a)	50	°C/W
R <sub>eJC</sub>	Thermal Resistance, Junction-to-Cas	SE (Note 1)	25	°C/W

Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHA	RACTERISTICS	<u> </u>					•
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$		-30			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -24 V, V <sub>GS</sub> = 0 V				-2	μΑ
			T <sub>J</sub> = 55°C			-25	μΑ
I <sub>GSSF</sub>	Gate - Body Leakage, Forward	V <sub>GS</sub> = 20 V, V <sub>DS</sub> = 0 V	·			100	nA
I <sub>GSSR</sub>	Gate - Body Leakage, Reverse	$V_{gs} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
ON CHAR	ACTERISTICS (Note 2)						
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$		-1	-1.6	-2.8	V
			T <sub>J</sub> = 125°C	-0.85	-1.25	-2.5	
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	$V_{gs} = -10 \text{ V}, I_{D} = -1.0 \text{ A}$			0.11	0.13	Ω
			T <sub>J</sub> = 125°C		0.15	0.21	
		$V_{GS} = -4.5 \text{ V}, I_{D} = -0.5 \text{ A}$			0.17	0.2	<u>]</u>
			T <sub>J</sub> = 125°C		0.24	0.32	
I <sub>D(on)</sub>	On-State Drain Current	$V_{GS} = -10 \text{ V}, V_{DS} = -5 \text{ V}$		-10			Α
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = -15 \text{ V}, I_{D} = -3.4 \text{ A}$			4		S
DYNAMIC	CHARACTERISTICS						
C <sub>iss</sub>	Input Capacitance	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			350		pF
C <sub>oss</sub>	Output Capacitance				260		pF
C <sub>rss</sub>	Reverse Transfer Capacitance				100		pF
SWITCHI	NG CHARACTERISTICS (Note 2)						
$t_{D(on)}$	Turn - On Delay Time	$V_{DD} = -10 \text{ V}, I_{D} = -1 \text{ A},$ $V_{GEN} = -10 \text{ V}, R_{GEN} = 6 \Omega$			9	40	ns
t,	Turn - On Rise Time				21	40	ns
$t_{D(off)}$	Turn - Off Delay Time				21	90	ns
t <sub>r</sub>	Turn - Off Fall Time				8	50	ns
$Q_g$	Total Gate Charge	$V_{DS} = -10 \text{ V},$ $I_{D} = -3.4 \text{ A}, V_{OS} = -10 \text{ V}$			10	25	nC
$Q_{gs}$	Gate-Source Charge	$I_D = -3.4 \text{ A}, \ V_{GS} = -10 \text{ V}$			1.6		nC
$Q_{gd}$	Gate-Drain Charge				3.4		nC

Electrical Characteristics (T <sub>A</sub> = 25°C unless otherwise noted)							
Symbol	Parameter Conditions		Min	Тур	Max	Units	
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS							
Is	Maximum Continuous Drain-Source Diode Forward Current				-1.9	Α	
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = -1.25 A (Note 2)		-0.8	-1.3	V	
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_F = -2.0 \text{ A}, dI_F/dt = 100 \text{ A/}\mu\text{s}$			100	ns	
I <sub>m</sub>	Reverse Recovery Current			1.9		Α	

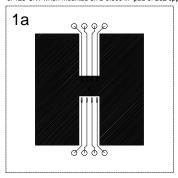
#### Notes:

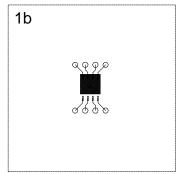
1.  $R_{g,k}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{g,c}$  is guaranteed by design while  $R_{g,c,k}$  is determined by the user's board design.

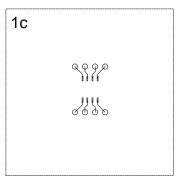
$$P_D(t) = \frac{T_{J-}T_A}{R_{\theta J} \dot{A}^{\dagger} t} = \frac{T_{J-}T_A}{R_{\theta J} \dot{c}^{\dagger} R_{\theta C} \dot{A}^{\dagger} t} = I_D^2(t) \times R_{DS (ON)} \mathbf{0}_{TJ}$$

Typical  $R_{\text{BJA}}$  using the board layouts shown below on 4.5"x5" FR-4 PCB in a still air environment:

- a. 50°C/W when mounted on a 1 in² pad of 2oz cpper.
- b. 105°C/W when mounted on a 0.04 in² pad of 2oz cpper.
- c. 125°C/W when mounted on a 0.006 in² pad of 2oz cpper.







Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width  $\leq$  300µs, Duty Cycle  $\leq$  2.0%.

# **Typical Electrical Characteristics**

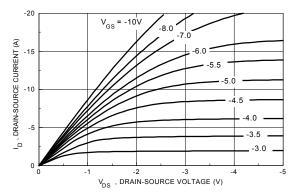


Figure 1. On-Region Characteristics.

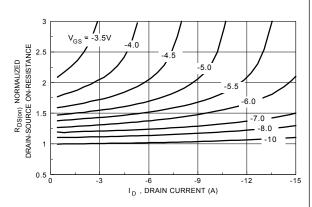


Figure 2. On-Resistance Variation with Gate Voltage and Drain Current.

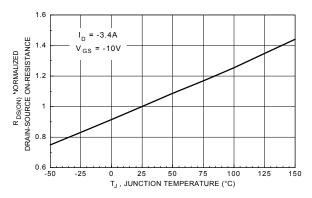


Figure 3. On-Resistance Variation with Temperature.

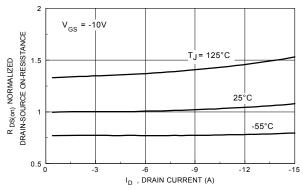


Figure 4. On-Resistance Variation with Drain Current and Temperature.

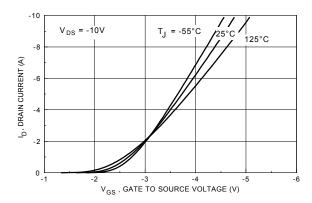


Figure 5. Transfer Characteristics.

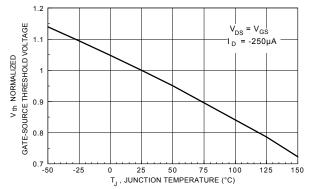


Figure 6. Gate Threshold Variation with Temperature.

# **Typical Electrical Characteristics** (continued)

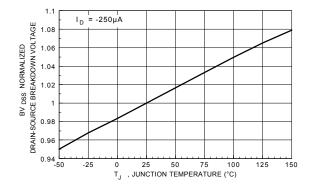


Figure 7. Breakdown Voltage Variation with Temperature.

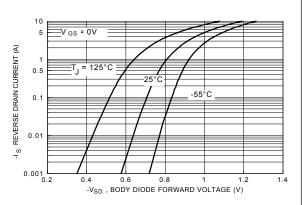


Figure 8. Body Diode Forward Voltage
Variation with Current and Temperature.

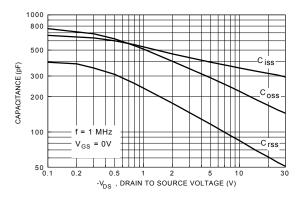


Figure 9. Capacitance Characteristics.

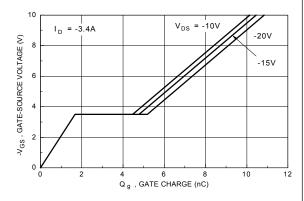


Figure 10. Gate Charge Characteristics.

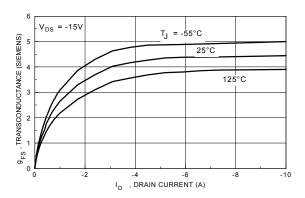


Figure 11. Transconductance Variation with Drain Current and Temperature.

# **Typical Thermal Characteristics**

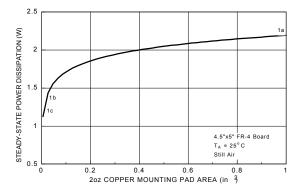


Figure 12. SO-8 Dual Package Maximum Steady-State Power Dissipation versus Copper Mounting Pad Area.

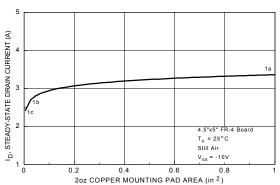


Figure 13. Maximum Steady- State Drain
Current versus Copper Mounting Pad
Area.

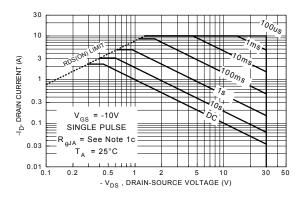


Figure 14. Maximum Safe Operating Area.

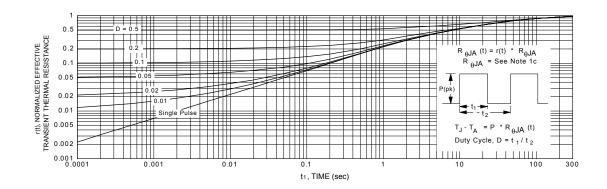


Figure 15. Transient Thermal Response Curve.

Note: Thermal characterization performed using the conditions described in note 1c. Transient thermal response will change depending on the circuit board design.

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